

<b>Notice of References Cited</b>	Application/Control No. 10/043,237		Applicant(s)/Patent Under Reexamination DOUMAE, YASUHIRO	
	Examiner William C. Vesperman		Art Unit 2813	Page 1 of 1

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"A Novel Self-aligned Gate-overlapped LDD Poly-Si TFT with High Reliability and Performance", published in the IEEE in 1977 and authored by Mutsuko Hatano, Hajime Akimoto and Takeshi Sakai.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.